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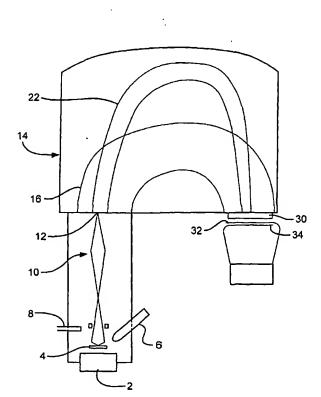
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(54) Title: CHARGED PARTICLE SPECTROMETER AND DETECTOR THEREFOR



(57) Abstract: A charged particle (e.g. photoelectron) spectrometer is operable in a first mode to produce an energy spectrum relating to the composition of a sample being analysed, and in a second mode to produce a charged particle image of the surface of the sample being analysed. A detector is used to detect charged particles produced in both modes of operation. A method of operation of the spectrometer includes the step of selecting which of said first and second modes to use and the detector being operated accordingly.

WO 2004/042775 A2



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